

Search Notes

Application/Control No.

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Examiner

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Applicant(s)/Patent under
Reexamination

JANG, DEOK HWAN

Art Unit

2681

SEARCHED

Class	Subclass	Date	Examiner
455	415	10/4/2005	HN
	410		
	411		
	418		
	422.1		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East (USPAT, US-PGPUB, EPO, JPO, DERWENT) - See search history printout.	10/4/2005	HN

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